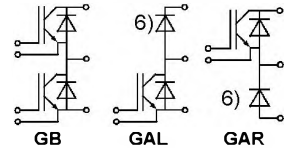


## SEMİTRANS® M IGBT Modules

**SKM 300 GB 123 D**  
**SKM 300 GAL 123 D <sup>6)</sup>**  
**SKM 300 GAR 123 D <sup>6)</sup>**



### SEMİTRANS 3



#### Features

- MOS input (voltage controlled)
- N channel, Homogeneous Si
- Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to  $6 \cdot I_{cnom}$
- Latch-up free
- Fast & soft inverse CAL diodes<sup>8)</sup>
- Isolated copper baseplate using DCB Direct Copper Bonding Technology
- Large clearance (12 mm) and creepage distances (20 mm)

#### Typical Applications: → B6 - 79

- Switching, not for linear use
- AC-inverter drives
- UPS

<sup>1)</sup>  $T_{case} = 25\text{ °C}$ , unless otherwise specified

<sup>2)</sup>  $I_F = -I_C$ ,  $V_R = 600\text{ V}$ ,  $-di/dt = 2000\text{ A}/\mu\text{s}$ ,  $V_{GE} = 0\text{ V}$

<sup>3)</sup> Use  $V_{Goff} = -5 \dots -15\text{ V}$

<sup>5)</sup> see fig. 2 + 3;  $R_{Goff} = 4,7\ \Omega$

<sup>6)</sup> The free-wheeling diodes of the GAL and GAR types have the data of the inverse diodes of SKM 400 GA 123 D

<sup>8)</sup> CAL = Controlled Axial Lifetime Technology.

**Cases and mech. data → B6-100 SEMİTRANS 3**

Absolute Maximum Ratings		Values		Units
Symbol	Conditions <sup>1)</sup>			
$V_{CES}$		1200		V
$V_{CGR}$	$R_{GE} = 20\text{ k}\Omega$	1200		V
$I_C$	$T_{case} = 25/80\text{ °C}$	290 / 200		A
$I_{CM}$	$T_{case} = 25/80\text{ °C}$ ; $t_p = 1\text{ ms}$	580 / 400		A
$V_{GES}$		$\pm 20$		V
$P_{tot}$	per IGBT, $T_{case} = 25\text{ °C}$	1400		W
$T_j$ , ( $T_{stg}$ )		- 40 ... +150 (125)		°C
$V_{isol}$	AC, 1 min.	2 500		V
humidity	DIN 40 040	Class F		
climate	DIN IEC 68 T.1	55/150/56		
<b>Inverse Diode</b>				
$I_F = -I_C$	$T_{case} = 25/80\text{ °C}$	260 / 180	FWD <sup>6)</sup>	A
$I_{FM} = -I_{CM}$	$T_{case} = 25/80\text{ °C}$ ; $t_p = 1\text{ ms}$	600 / 400	580 / 400	A
$I_{FSM}$	$t_p = 10\text{ ms}$ ; $\sin$ ; $T_j = 150\text{ °C}$	2200	2900	A
$t^*t$	$t_p = 10\text{ ms}$ ; $T_j = 150\text{ °C}$	24200	42000	A <sup>2</sup> s

Characteristics		min.	typ.	max.	Units
Symbol	Conditions <sup>1)</sup>				
$V_{I(BR)CES}$	$V_{GE} = 0$ , $I_C = 4\text{ mA}$	$\geq V_{CES}$	-	-	V
$V_{GE(th)}$	$V_{GE} = V_{CES}$ , $I_C = 8\text{ mA}$	4,5	5,5	6,5	V
$I_{CES}$	$V_{GE} = 0$   $T_j = 25\text{ °C}$	-	3	4,5	mA
	$V_{CE} = V_{CES}$   $T_j = 125\text{ °C}$	-	15	-	mA
$I_{GES}$	$V_{GE} = 20\text{ V}$ , $V_{CE} = 0$	-	-	0,4	$\mu\text{A}$
$V_{CESat}$	$I_C = 200\text{ A}$   $V_{GE} = 15\text{ V}$ ;	-	2,5(3,1)	3(3,7)	V
$V_{CESat}$	$I_C = 300\text{ A}$   $T_j = 25\text{ (125) °C}$	-	3(3,8)	-	V
$g_{fs}$	$V_{CE} = 20\text{ V}$ , $I_C = 200\text{ A}$	108	150	-	S
$C_{CHC}$	per IGBT	-	-	700	pF
$C_{ies}$	$V_{GE} = 0$	-	18	24	nF
$C_{oes}$	$V_{CE} = 25\text{ V}$	-	2,5	3,2	nF
$C_{res}$	$f = 1\text{ MHz}$	-	1,0	1,3	nF
$L_{CE}$		-	-	20	nH
$t_{d(on)}$	$V_{CC} = 600\text{ V}$	-	250	400	ns
$t_r$	$V_{GE} = +15\text{ V} / -15\text{ V}^{3)}$	-	90	160	ns
$t_{d(off)}$	$I_C = 200\text{ A}$ , ind. load	-	550	700	ns
$t_f$	$R_{Gon} = R_{Goff} = 4,7\ \Omega$	-	70	100	ns
$E_{on}^{5)}$	$T_j = 125\text{ °C}$	-	28	-	mWs
$E_{off}^{5)}$		-	26	-	mWs
<b>Inverse Diode <sup>8)</sup></b>					
$V_F = V_{EC}$	$I_F = 200\text{ A}$   $V_{GE} = 0\text{ V}$ ;	-	2,0(1,8)	2,5	V
$V_F = V_{EC}$	$I_F = 300\text{ A}$   $T_j = 25\text{ (125) °C}$	-	2,25(2,1)	-	V
$V_{TO}$	$T_j = 125\text{ °C}$	-	1,1	1,2	V
$r_T$	$T_j = 125\text{ °C}^{2)}$	-	3	5,5	m $\Omega$
$I_{RRM}$	$I_F = 200\text{ A}$ ; $T_j = 25\text{ (125) °C}^{2)}$	-	70(105)	-	A
$Q_{rr}$	$I_F = 200\text{ A}$ ; $T_j = 25\text{ (125) °C}^{2)}$	-	10(26)	-	$\mu\text{C}$
<b>FWD of type "GAL" and "GAR" <sup>8)6)</sup></b>					
$V_F = V_{EC}$	$I_F = 200\text{ A}$   $V_{GE} = 0\text{ V}$ ;	-	1,9(1,7)	2,4	V
$V_F = V_{EC}$	$I_F = 300\text{ A}$   $T_j = 25\text{ (125) °C}$	-	2,1(1,8)	-	V
$V_{TO}$	$T_j = 125\text{ °C}$	-	-	1,2	V
$r_T$	$T_j = 125\text{ °C}$	-	3	3,5	m $\Omega$
$I_{RRM}$	$I_F = 200\text{ A}$ ; $T_j = 25\text{ (125) °C}^{2)}$	-	80(140)	-	ns
$Q_{rr}$	$I_F = 200\text{ A}$ ; $T_j = 25\text{ (125) °C}^{2)}$	-	10(34)	-	$\mu\text{C}$
<b>Thermal Characteristics</b>					
$R_{thjc}$	per IGBT	-	-	0,09	°C/W
$R_{thjc}$	per diode / FWD <sup>6)</sup>	-	-	0,18/0,15	°C/W
$R_{thch}$	per module	-	-	0,038	°C/W

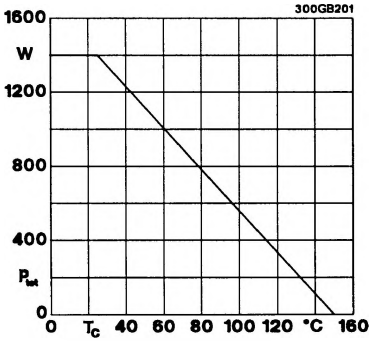


Fig. 1 Rated power dissipation  $P_{tot} = f(T_c)$

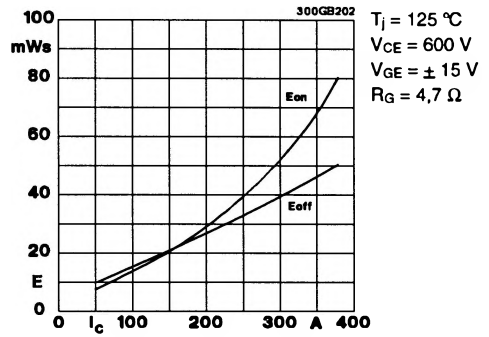


Fig. 2 Turn-on /-off energy  $= f(I_c)$

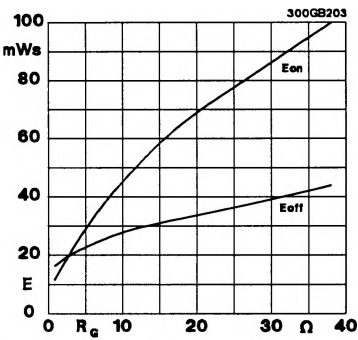


Fig. 3 Turn-on /-off energy  $= f(R_G)$

$T_j = 125\text{ }^\circ\text{C}$   
 $V_{CE} = 600\text{ V}$   
 $V_{GE} = \pm 15\text{ V}$   
 $I_c = 200\text{ A}$

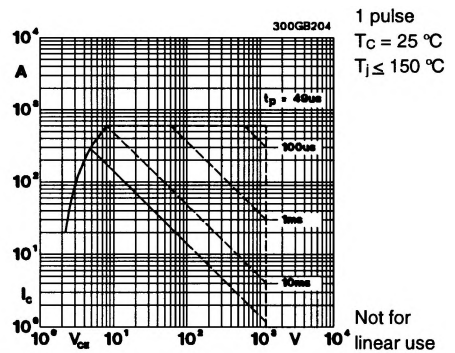


Fig. 4 Maximum safe operating area (SOA)  $I_c = f(V_{ce})$

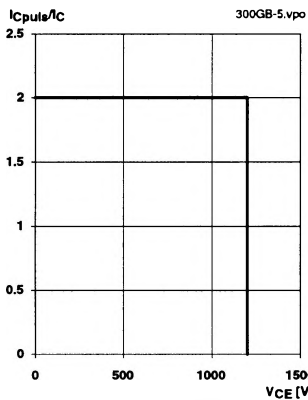


Fig. 5 Turn-off safe operating area (RBSOA)

$T_j \leq 150\text{ }^\circ\text{C}$   
 $V_{GE} = 15\text{ V}$   
 $R_{G(off)} = 4,7\text{ }\Omega$   
 $I_c = 200\text{ A}$

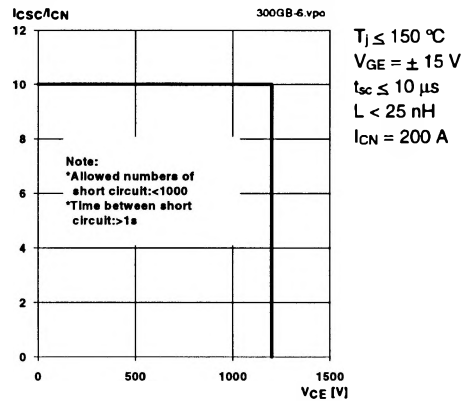


Fig. 6 Safe operating area at short circuit  $I_c = f(V_{ce})$

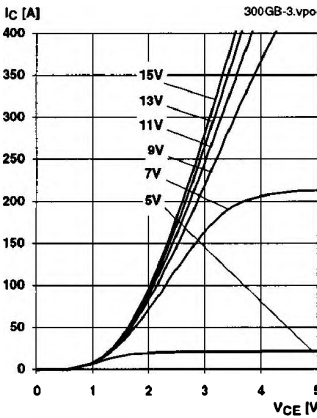


Fig. 9 Typ. output characteristic,  $t_p = 80 \mu s$ ;  $25 \text{ }^\circ\text{C}$

$$P_{cond(t)} = V_{CEsat(t)} \cdot I_c(t)$$

$$V_{CEsat(t)} = V_{CE(TO)(Tj)} + r_{CE(Tj)} \cdot I_c(t)$$

$$V_{CE(TO)(Tj)} \leq 1.5 + 0.002 (T_j - 25) \text{ [V]}$$

$$r_{CE(Tj)} = 0.005 + 0.00002 (T_j - 25) \text{ [\Omega]}$$

$$\text{valid for } V_{GE} = +15 \begin{matrix} +2 \\ -1 \end{matrix} \text{ [V]; } I_c > 0.3 I_{Cnom}$$

Fig. 11 Typ. saturation characteristic (IGBT)  
Calculation elements and equations

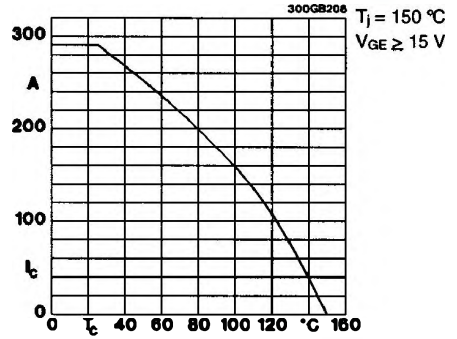


Fig. 8 Rated current vs. temperature  $I_c = f(T_c)$

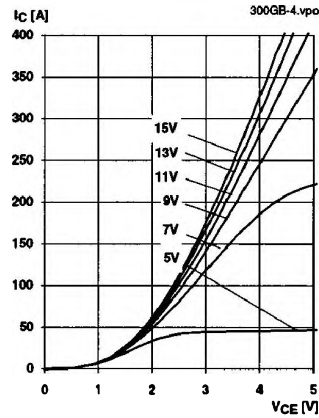


Fig. 10 Typ. output characteristic,  $t_p = 80 \mu s$ ;  $125 \text{ }^\circ\text{C}$

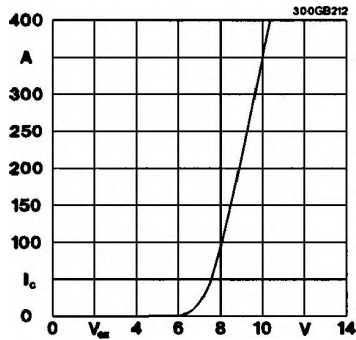


Fig. 12 Typ. transfer characteristic,  $t_p = 80 \mu s$ ;  $V_{CE} = 20 \text{ V}$

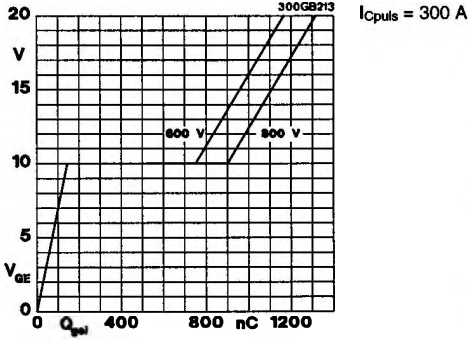


Fig. 13 Typ. gate charge characteristic

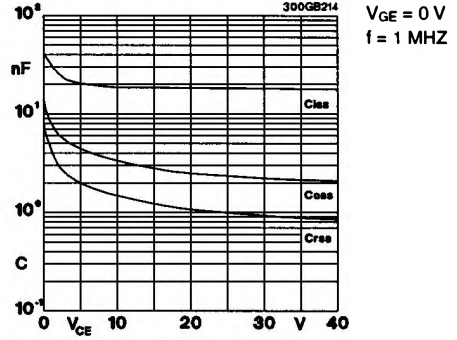


Fig. 14 Typ. capacitances vs.  $V_{CE}$

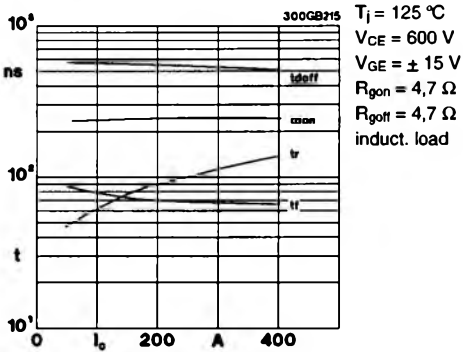


Fig. 15 Typ. switching times vs.  $I_C$

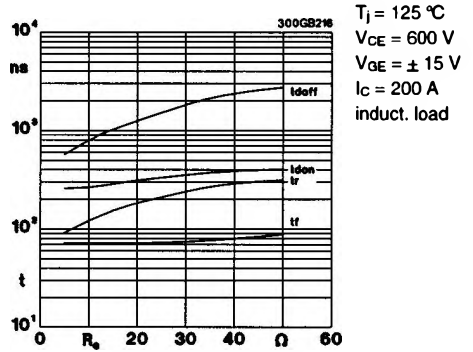


Fig. 16 Typ. switching times vs. gate resistor  $R_g$

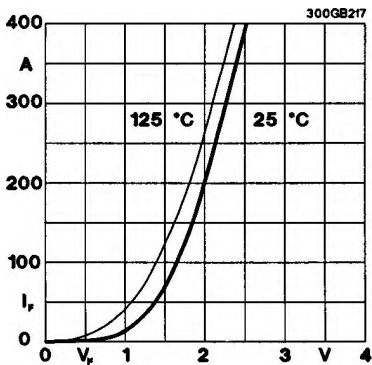


Fig. 17 Typ. CAL diode forward characteristic

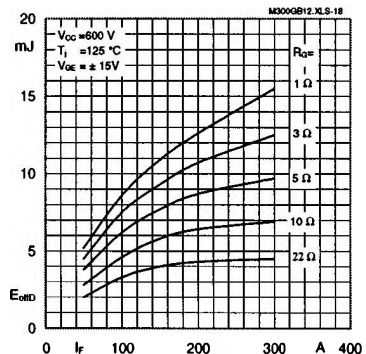


Fig. 18 Diode turn-off energy dissipation per pulse

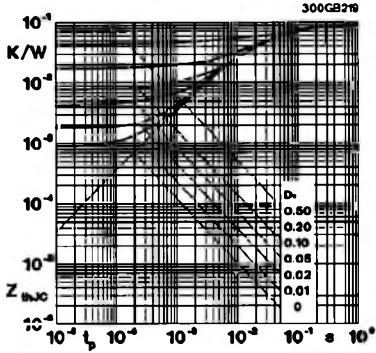


Fig. 19 Transient thermal impedance of IGBT  
 $Z_{thJC} = f(t_p)$ ;  $D = t_p / t_c = t_p \cdot f$

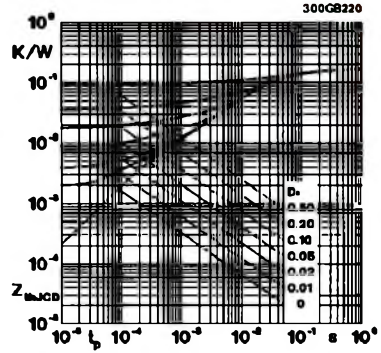


Fig. 20 Transient thermal impedance of inverse CAL diodes  
 $Z_{thJC} = f(t_p)$

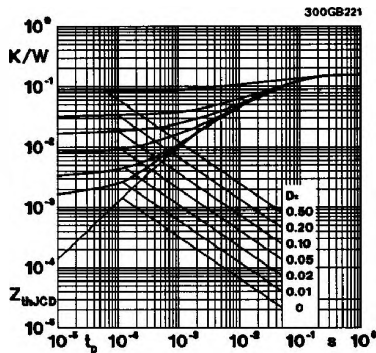


Fig. 21 Transient thermal impedance of the freewheeling diode  
 $Z_{thJC} \rightarrow B 6 - 95, \text{ rem. } 6)$

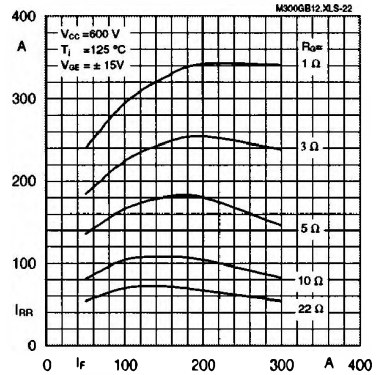


Fig. 22 Typ CAL diode reverse recovery current  $I_{RR} = f(I_F, R_G)$

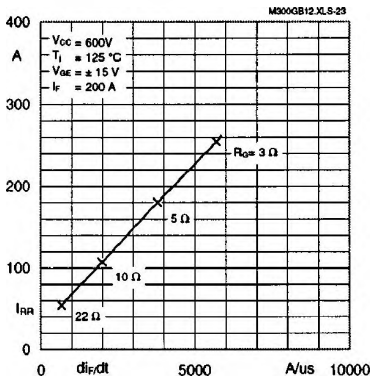


Fig. 23 Typ. CAL diode reverse recovery current  $I_{RR} = f(di_F/dt; R_G)$

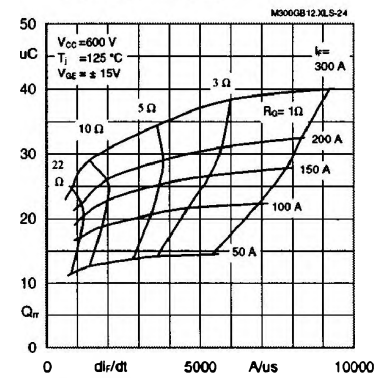
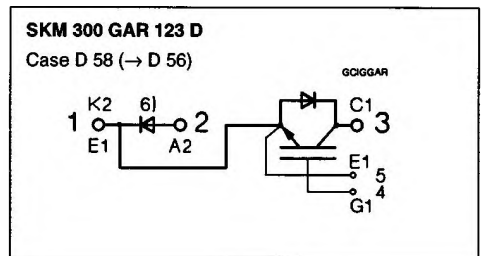
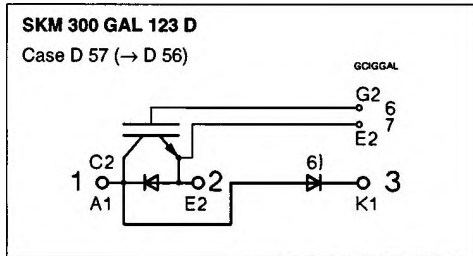
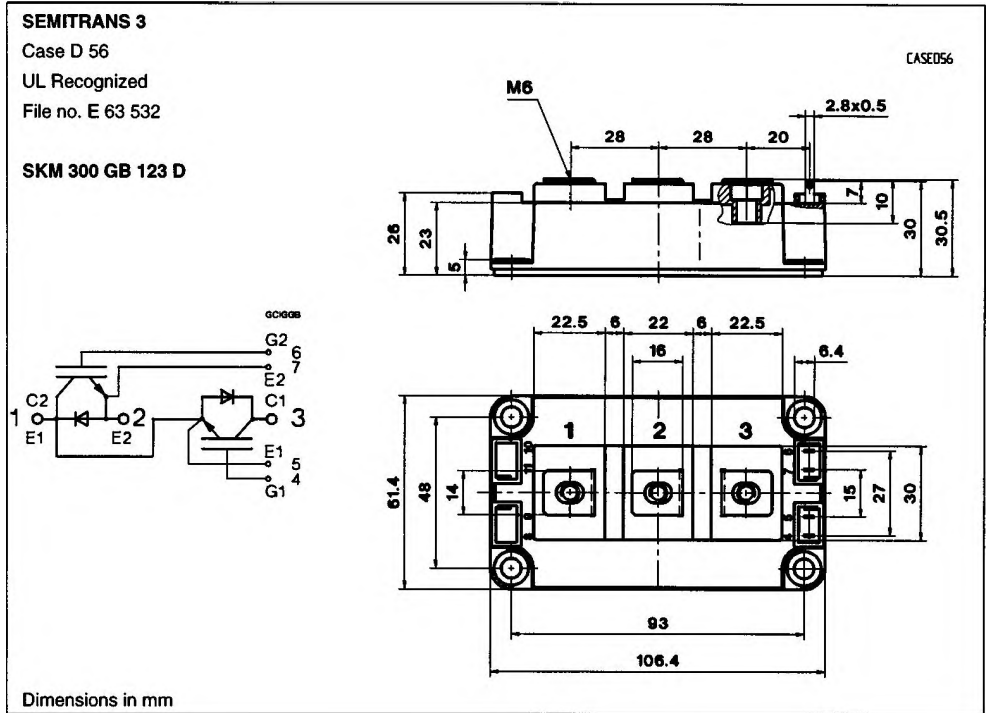


Fig. 24 Typ. CAL diode recovered charge  $Q_{rr} = f(di_F/dt; I_F; R_G)$



Case outline and circuit diagrams

Mechanical Data		Values			Units
Symbol	Conditions	min.	typ.	max.	
M <sub>1</sub>	to heatsink, SI Units to heatsink, US Units	(M6) 3	—	5	Nm lb.in.
M <sub>2</sub>	for terminals, SI Units for terminals US Units	(M6) 2,5	—	5	Nm lb.in.
a		—	—	5x9,81	m/s <sup>2</sup>
w		—	—	420	g

This is an electrostatic discharge sensitive device (ESDS). Please observe the international standard IEC 747-1, Chapter IX.

Three devices are supplied in one SEMIBOX A without mounting hardware, which can be ordered separately under Ident No. 33321100 (for 10 SEMISTRANS 3). Larger packing units of 12 and 20 pieces are used if suitable

Accessories → page B 6 - 4.  
 SEMIBOX → page C - 1.

<sup>6)</sup> Freewheeling diode → page B 6 - 95, remark 6.